

CPE 323: AD and DA Converter

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Outline

- Principles of Analog-to-Digital Conversion
- MSP430 ADC12 Peripheral
- MSP430 ADC12 Demo
- MSP430 DAC12 Peripheral
- MSP430 DAC12 Demo





Principles of Analog-to-Digital Conversion

- Physical world is analog
- Need to measure physical quantities
- Transducers convert physical quantities into electrical signals (voltage, current)
- ADC: devices that carry out conversion from analog to digital domain (values that can be processed in digital computers)



Flow in Analog-to-Digital Conversion

- Signal conditional block
- Analog multiplexer

ADC12

- Sample-and-hold circuit
- A/D Converter core
- A/D Buffer

Signal conditional block

DAC12 Demo

- Isolation and buffering: protect ADC from dangerous voltages and static discharges
- Amplification: ensure that full-scale analog input result in full-scale digital signal
 - E.g., ECG signal (1 mV)
- Bandwidth limiting: filters
 - E.g., ECG is buried in noise, filter signal out

ADC Modules

DAC12 Demo

- Analog multiplexer
 - Often multiple analog signals that needs to be digitized share a single ADC core
- Sample-and-hold circuit
 - Problem:
 - Conversion time: time required to carry out conversion
 - Analog signals change during this time (influencing conversion result)
 - Solution: sample the signal and hold it steady until conversion is done



ADC Modules

- A/D Converter core
 - Converts analog signal to digital counterpart
- A/D Buffers
 - Digital values are stored in local buffers before they are transferred to main memory for further buffering and processing

Definitions: ADC Resolution

- Number of discrete values it can produce over the range of analog values
- Usually expressed in bits
- ADC with a resolution of 8 bits can encode an analog input to one in 256 different levels, since $2^8 = 256$
 - Ranges from 0 to 255 (i.e. unsigned integer) or from −128 to 127 (i.e. signed integer)

Definitions: ADC Resolution (cont'd)

- Can be defined electrically and expressed in Volts
- The smallest change in the input signal that will produce a change in the output digital code;
 Assume N-bit ADC
 - $V_R = V_{FUII-SCALF}/2^N$
 - E.g., V_{FULL-SCALE}=3V, N=12, V_R=0.73mV
- The minimum change to guarantee a change in the output code level is called the least significant bit (LSB) voltage



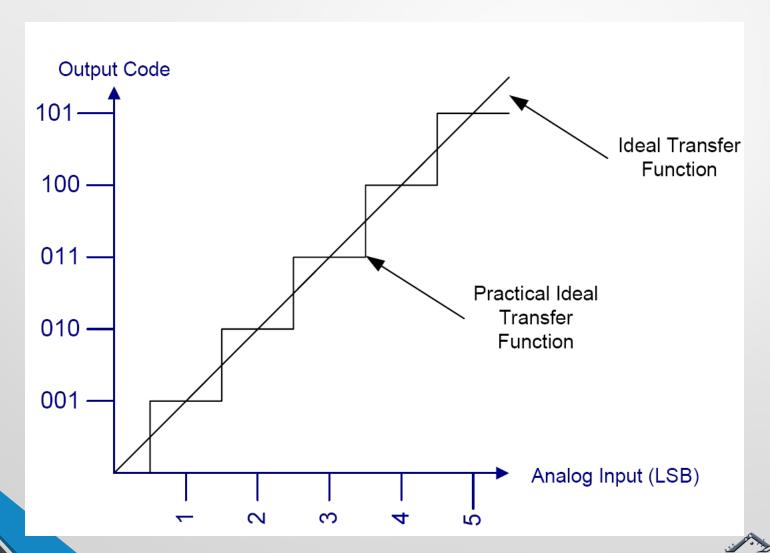
Definitions: Accuracy

- An ADC has several sources of errors
- Quantization error (due to finite resolution)
 - Difference between the original signal and the digitized signal
- Non-linearity
 - Any deviations from intended liner transfer function
- Aperture error
 - Due to a clock jitter and is revealed when digitizing a time-variant signal (not a constant value)



Definitions: Transfer Function

DAC12 Demo





Definitions: Aperture Time, Conversion Time

Aperture time

ADC12

- Time the AD is looking at the signal
- Think about it as a capacitor that needs some time to get fully charged
- Conversion time
 - Time required to complete conversion of the input signal





Definitions: Sampling frequency

- Analog signal is continuous in time and it is necessary to convert this to a flow of digital values
- Sampling frequency/rate: the rate of new values
- Continuously varying signal can be sampled and then reproduced from the discrete-time values
- Reproduction is possible if the sampling rate is higher than twice the highest frequency of the signal (the Shannon-Nyquist sampling theorem)



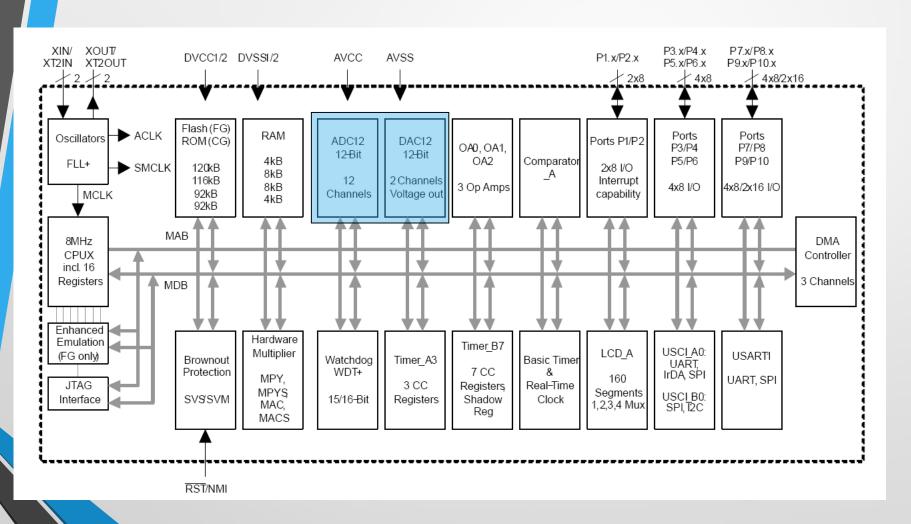
A/D Converter Types

- Successive approximation (slower)
- Parallel (fast and expensive)





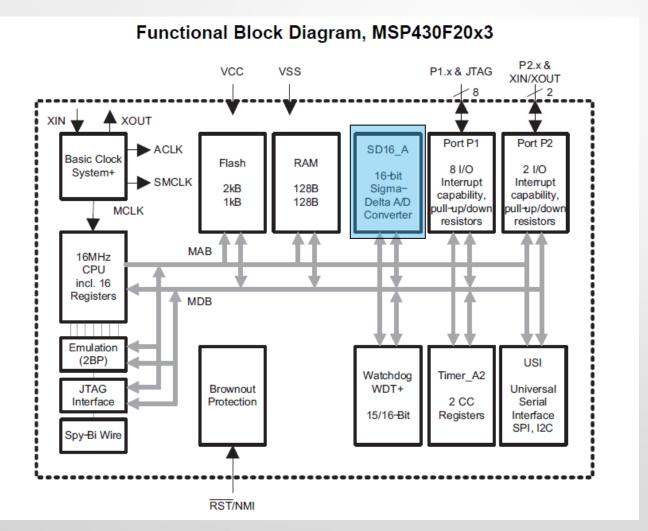
MSP430xG461x Microcontroller



ADC12 Demo



MSP430xF20x3 Microcontroller





ADC12 Introduction

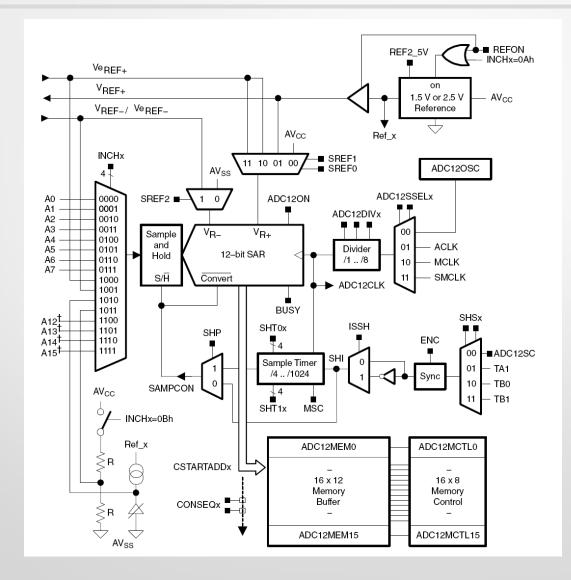
DAC12 Demo

- ADC12 module supports fast, 12-bit analog-to-digital conversions
 - 12-bit SAR core, sample select control, reference generator and a 16 word conversion-and-control buffer
 - Conversion-and-control buffer allows up to 16 independent ADC samples to be converted and stored without any CPU intervention
- ADC12 features include
 - Greater than 200 ksps maximum conversion rate; Monotonic 12-bit converter with no missing codes
 - Sample-and-hold with programmable sampling periods controlled by software or timers
 - Conversion initiation by software, Timer A, or Timer B
 - Software selectable internal or external reference; selectable on-chip reference voltage generation (1.5 V or 2.5 V)
 - Eight individually configurable external input channels
 - Conversion channels for internal temperature sensor, AV_{CC}, and external references
 - Independent channel-selectable reference sources for both positive and negative references
 - Selectable conversion clock source
 - Single-channel, repeat-single-channel, sequence, and repeat-sequence conversion modes
 - ADC core and reference voltage can be powered down separately
 - Interrupt vector register for fast decoding of 18 ADC interrupts; 16 conversion-result storage registers





ADC12 Block Diagram





ADC Core

DAC12 Demo

Core converts an analog input to its 12-bit digital representation an stores the result in conversion memory; the conversion formula is

$$N_{ADC} = 4095 \cdot \frac{V_{in} - V_{R-}}{V_{R+} - V_{R-}}$$

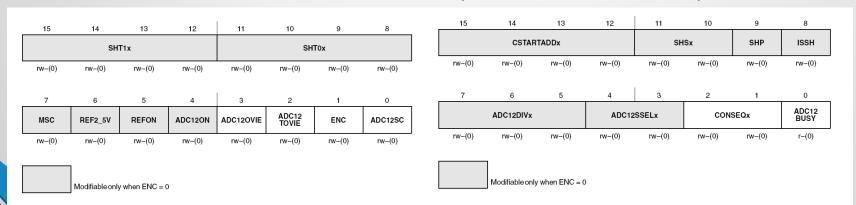
- V_{R+} and V_{R-} are programmable voltage levels: the upper (V_{R+}) and lower limits (V_{R-}) of the conversion
- The digital output (NADC) is full scale
 - (OFFFh) when the input signal is equal to or higher than V_{R+}
 - Oh when the input signal is equal to or lower than V_{R-}
 - The input channel and the reference voltage levels (V_{R+} and V_{R-}) are defined in the conversion-control memory.
- NADC = nint($(2^{N}-1)*V_{IN}/V_{FS}$), where nint gives the nearest integer to the argument





Core Configuration

- Two control registers, ADC12CTL0 and ADC12CTL1
- The core is enabled with the ADC12ON bit
 - The ADC12 can be turned off when not in use to save power
- With few exceptions the ADC12 control bits can only be modified when ENC = 0
 - ENC must be set to 1 before any conversion can take place







Conversion Clock Selection

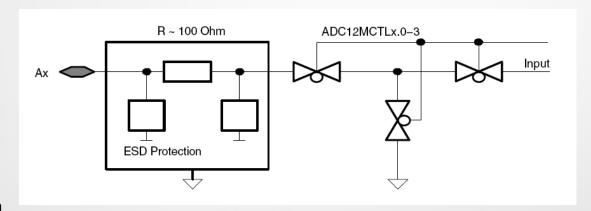
- ADC12CLK is used both as the conversion clock and to generate the sampling period when the pulse sampling mode is selected
- Source clock selection
 - ADC12SSELx bits to select a source: SMCLK, MCLK, ACLK, and the internal oscillator ADC12OSC
 - The ADC12OSC, generated internally, is in the 5-MHz range, but varies with individual devices, supply voltage, and temperature
 - See the device-specific datasheet for the ADC12OSC specification
 - Source clock can be divided from 1-8 using the ADC12DIVx bits
 - The user must ensure that the clock chosen for ADC12CLK remains active until the end of a conversion. If the clock is removed during a conversion, the operation will not complete and any result will be invalid





ADC12 Inputs

- 8 external and 4 internal analog signals are selected as the channel for conversion by the analog input multiplexer
- The input multiplexer is a break-before-make type to reduce input-to-input noise injection resulting from channel switching as shown below



- Port selection
 - ADC12 inputs are multiplexed with the port P6 pins, which are digital CMOS gates
 - Parasitic current problem
 - When analog signals are applied to digital CMOS gates, parasitic current can flow from VCC to GND. This parasitic current occurs if the input voltage is near the transition level of the gate
 - Disabling the port pin buffer eliminates the parasitic current flow and therefore reduces overall current consumption. The P6SELx bits provide the ability to disable the port pin input and output buffers



Voltage Reference Generator

DAC12 Demo

- Built-in voltage reference with two selectable voltage levels, 1.5 V and 2.5 V
 - Either may be used internally (REFON=1) and externally on pin Ve_{REF+}
 - When REF2_5V = 1, the internal reference is 2.5 V
 - When REF2_5V = 0, the reference is 1.5 V
 - The reference can be turned off to save power when not in use
 - For proper operation the internal voltage reference generator must be supplied with storage capacitance across VREF+ and AVSS. The recommended storage capacitance is a parallel combination of 10-µF and 0.1-µF capacitors
 - From turn-on, a minimum of 17 ms must be allowed for the voltage reference generator to bias the recommended storage capacitors.
- External references may be supplied for V_{R+} and V_{R-} through pins Ve_{REF+} and V_{RFF-}/Ve_{RFF-} respectively





Auto Power-down

- Designed for low power applications
 - When the ADC12 is not actively converting, the core is automatically disabled and automatically re-enabled when needed.
 - The ADC12OSC is also automatically enabled when needed and disabled when not needed.
- The reference is not automatically disabled, but can be disabled by setting REFON = 0. When the core, oscillator, or reference are disabled, they consume no current



Sample-and-Hold

- Needs to sample input before the conversion starts
- Input can be modeled as a capacitor
 - Must be fully charged and the time needed usually sets the maximum speed of the converter
- N=12 => want error to be less than (½)LSB (1/2¹³)
- Time to charge capacitor: e^{-t}/tau < 2⁻¹³ => tau is time constant that corresponds to RC of the input circuitry => t>9tau



Sample Timing

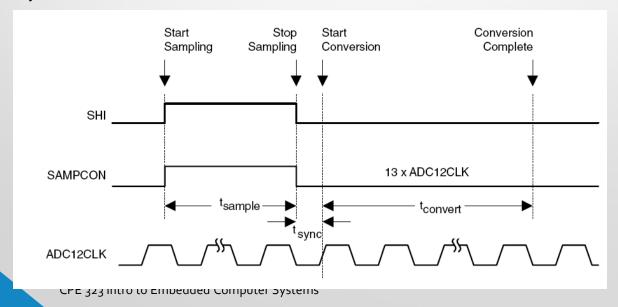
- An analog-to-digital conversion is initiated with a rising edge of the sample input signal SHI
- The source for SHI is selected with the SHSx bits and includes the following:
 - The ADC12SC bit
 - The Timer A Output Unit 1
 - The Timer B Output Unit 0
 - The Timer B Output Unit 1
- The polarity of the SHI signal source can be inverted with the ISSH bit.
- The SAMPCON signal controls the sample period and start of conversion. When SAMPCON is high, sampling is active. The high-tolow SAMPCON transition starts the analog-to-digital conversion, which requires 13 ADC12CLK cycles.
- Two different sample-timing methods are defined by control bit SHP, extended sample mode and pulse mode.





Extended Sample Mode

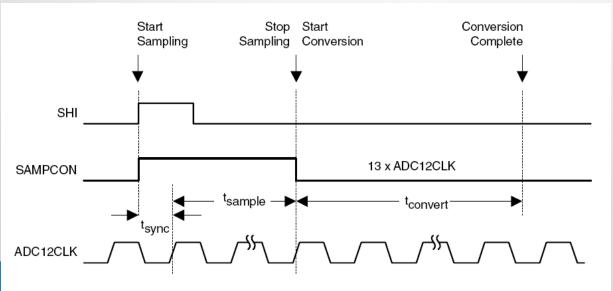
- Selected when SHP = 0
- The SHI signal directly controls SAMPCON and defines the length of the sample period tsample
 - When SAMPCON is high, sampling is active
 - The high-to-low SAMPCON transition starts the conversion after synchronization with ADC12CLK





Pulse Sample Mode

- Selected when SHP = 1
- The SHI signal is used to trigger the sampling timer
- The SHT0x and SHT1x bits in ADC12CTL0 control the interval of the sampling timer that defines the SAMPCON sample period tsample.
- The sampling timer keeps SAMPCON high after synchronization with AD12CLK for a programmed interval tsample. The total sampling time is tsample plus tsync.
- The SHTx bits select the sampling time in 4x multiples of ADC12CLK. SHT0x selects the sampling time for ADC12MCTL0 to 7 and SHT1x selects the sampling time for ADC12MCTL8 to 15.

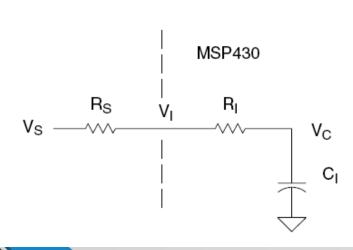






Sample Time Consideration

- When SAMPCON = 0 all Ax inputs are high impedance
- When SAMPCON = 1, the selected Ax input can be modeled as an RC low-pass filter during the sampling time tsample (see below)
- An internal MUX-on input resistance RI (max. 2 k Ω) in series with capacitor CI (max. 40 pF) is seen by the source. The capacitor CI voltage VC must be charged to within LSB of the source voltage VS for an accurate 12-bit conversion
 - tsample > $(RS+RI)\ln(2^{13})CI + 800ns$
 - tsample > (RS + 2k)9.011x40pF + 800ns; if RS is 10 k Ω , tsample must be greater than 5.13 μ s.



 V_{I} = Input voltage at pin Ax

V_S = External source voltage

R_S = External source resistance

R_I = Internal MUX-on input resistance

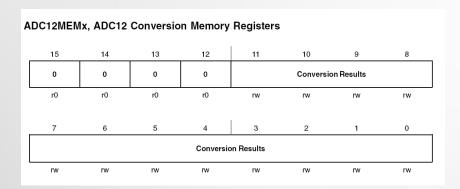
C_I = Input capacitance

 V_C = Capacitance-charging voltage

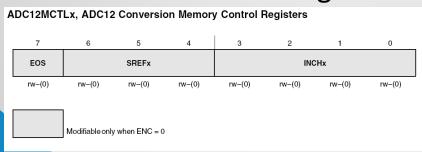
Conversion Memory

DAC12 Demo

16 ADC12MEMx conversion memory registers to store conversion results



Each ADC12MEMx is configured with an associated ADC12MCTLx control register







Conversion Memory (cont'd)

- SREFx bits define the voltage reference
- INCHx bits select the input channel
- EOS bit defines the end of sequence when a sequential conversion mode is used
 - A sequence rolls over from ADC12MEM15 to ADC12MEM0 when the EOS bit in ADC12MCTL15 is not set
- CSTARTADDx bits define the first ADC12MCTLx used for any conversion
 - If the conversion mode is single-channel or repeat-single-channel the CSTARTADDx points to the single ADC12MCTLx to be used
 - If the conversion mode selected is either sequence-of-channels or repeat-sequence-ofchannels, CSTARTADDx points to the first ADC12MCTLx location to be used in a sequence.
- A pointer, not visible to software, is incremented automatically to the next ADC12MCTLx in a sequence when each conversion completes. The sequence continues until an EOS bit in ADC12MCTLx is processed - this is the last control byte processed.
- When conversion results are written to a selected ADC12MEMx, the corresponding flag in the ADC12IFGx register is set





Conversion Modes

Determined by CONSEQx bits

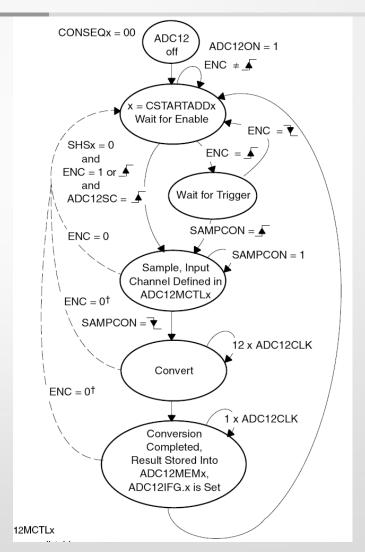
CONSEQx	Mode	Operation
00	Single channel single-conversion	A single channel is converted once.
01	Sequence-of- channels	A sequence of channels is converted once.
10	Repeat-single- channel	A single channel is converted repeatedly.
11	Repeat-sequence- of-channels	A sequence of channels is converted repeatedly.



Single-Channel, Single **Conversion Mode**

DAC12 Demo

- A single channel is sampled and converted once
- The ADC result is written to the ADC12MEMx defined by the **CSTARTADDx** bits
- When ADC12SC triggers a conversion, successive conversions can be triggered by the ADC12SC bit
- When any other trigger source is used, ENC must be toggled between each conversion

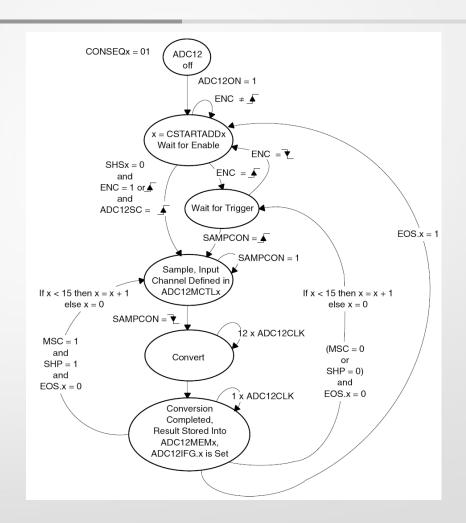






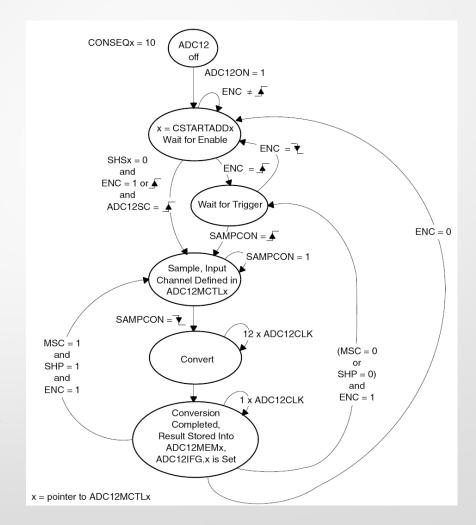
Sequence-of-Channels Mode

- A sequence of channels is sampled and converted once.
- The ADC results are written to the conversion memories starting with the ADCMEMx defined by the CSTARTADDx bits.
- The sequence stops after the measurement of the channel with a set EOS bit.
- When ADC12SC triggers a sequence, successive sequences can be triggered by the ADC12SC bit.
- When any other trigger source is used, ENC must be toggled between each sequence.



Repeat-Single-Channel Mode

- A single channel is sampled and converted continuously.
- The ADC results are written to the ADC12MEMx defined by the CSTARTADDx bits.
 - It is necessary to read the result after the completed conversion because only one ADC12MEMx memory is used and is overwritten by the next conversion.

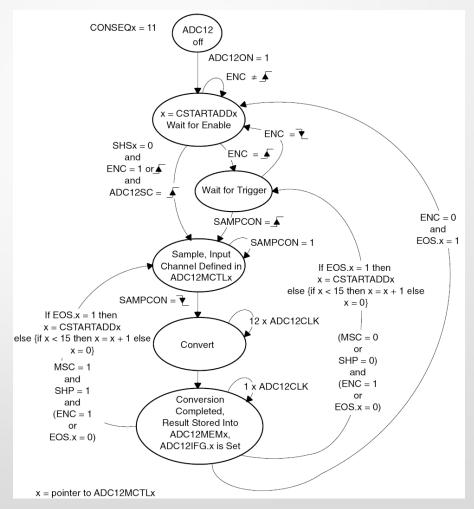






Repeat-Sequence-of-Channels Mode

- A sequence of channels is sampled and converted repeatedly.
- The ADC results are written to the conversion memories starting with the ADC12MEMx defined by the CSTARTADDx bits.
- The sequence ends after the measurement of the channel with a set EOS bit and the next trigger signal re-starts the sequence.



- Perform successive conversions automatically and as quickly as possible, a multiple sample and convert function is available
- When MSC = 1, CONSEQx > 0, and the sample timer is used, the first rising edge of the SHI signal triggers the first conversion.
- Successive conversions are triggered automatically as soon as the prior conversion is completed.
 - Additional rising edges on SHI are ignored until the sequence is completed in the single-sequence mode or until the ENC bit is toggled in repeat-single-channel, or repeated-sequence modes.
 - The function of the ENC bit is unchanged when using the MSC bit.



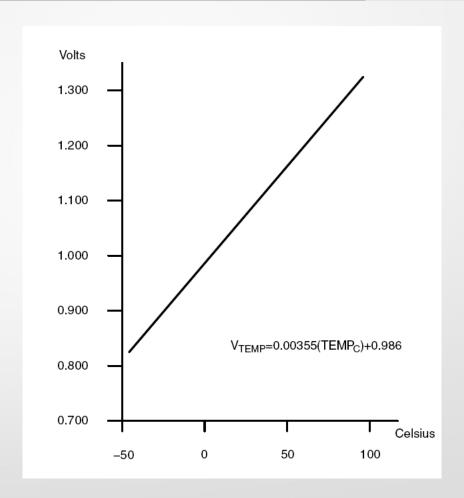
Stopping Conversions

- Depends on the mode of operation.
- Recommended ways to stop an active conversion or conversion sequence are
 - Resetting ENC in single-channel single-conversion mode stops a conversion immediately and the results are unpredictable.
 - For correct results, poll the busy bit until reset before clearing ENC.
 - Resetting ENC during repeat-single-channel operation stops the converter at the end of the current conversion.
 - Resetting ENC during a sequence or repeat-sequence mode stops the converter at the end of the sequence.
 - Any conversion mode may be stopped immediately by setting the CONSEQx = 0 and resetting ENC bit. Conversion data are unreliable.

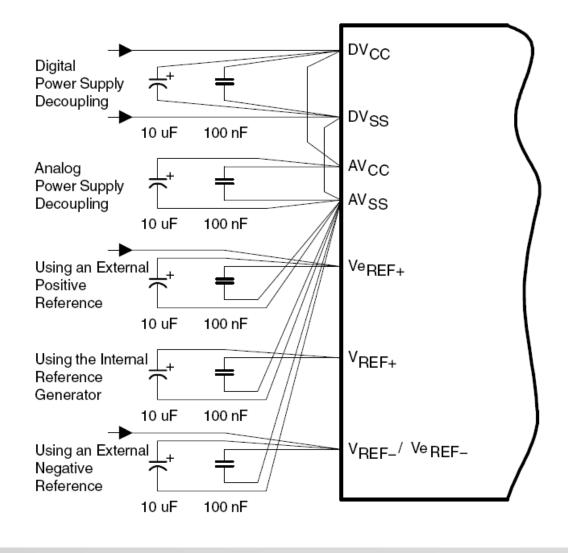


Temperature On-Chip Sensor

- Select INCHx = 1010
- Typical transfer function (check device specific datasheet)
- The sample period must be greater than 30 µs.
- Selecting the temperature sensor automatically turns on the on-chip reference generator as a voltage source for the temperature sensor
 - However, it does not enable the VREF+ output or affect the reference selections for the conversion.
 - The reference choices for converting the temperature sensor are the same as with any other channel.



ADC Grounding and Noise Considerations





ADC Interrupts

- The ADC12 has 18 interrupt sources:
 - ADC12IFG0-ADC12IFG15
 - ADC12OV, ADC12MEMx overflow
 - ADC12TOV, ADC12 conversion time overflow
- The ADC12IFGx bits are set when their corresponding ADC12MEMx memory register is loaded with a conversion result.
 - An interrupt request is generated if the corresponding ADC12IEx bit and the GIE bit are set.
- The ADC12OV condition occurs when a conversion result is written to any ADC12MEMx before its previous conversion result was read
- The ADC12TOV condition is generated when another sample-andconversion is requested before the current conversion is completed.



Interrupt Handling Routine

- The ADC12IV value is added to the PC to automatically jump to the appropriate routine.
 - The numbers at the right margin show the necessary CPU cycles for each instruction.
 - The software overhead for different interrupt sources includes interrupt latency and return-from-interrupt cycles, but not the task handling itself
 - The latencies are:
 - ADC12IFG0 ADC12IFG14, ADC12TOV and ADC12OV 16 cycles
 - ADC12IFG15 14 cycles
 - The interrupt handler for ADC12IFG15 shows a way to check immediately if a higher prioritized interrupt occurred during the processing of ADC12IFG15.
- This saves nine cycles if another ADC12 interrupt is pending.

```
; Interrupt handler for ADC12.
INT ADC12
                   ; Enter Interrupt Service Routine
   ADD
         &ADC12IV, PC; Add offset to PC
   RETI
                   ; Vector 0: No interrupt
   JMP
         ADOV
                   ; Vector 2: ADC overflow
   JMP
         ADTOV
                   ; Vector 4: ADC timing overflow
   JMP
         ADMO
                   ; Vector 6: ADC12IFG0
                   ; Vectors 8-32
   JMP
         ADM14
                   ; Vector 34: ADC12IFG14
; Handler for ADC12IFG15 starts here. No JMP required.
ADM15
        MOV &ADC12MEM15,xxx; Move result, flag is reset
                             ; Other instruction needed?
        JMP INT ADC12
                             ; Check other int pending
  ADC12IFG14-ADC12IFG1 handlers go here
ADM0
         MOV &ADC12MEM0,xxx ; Move result, flag is reset
                             ; Other instruction needed?
         RETI
                             : Return
ADTOV
                             ; Handle Conv. time overflow
         RETI
                             ; Return
ADOV
                             ; Handle ADCMEMx overflow
         RETI
                             ; Return
```



ADC12 Demo: A0 Compare

```
//*********************
//MSP430xG461x Demo - ADC12, Sample A0, Set P5.1 if A0 > 0.5*AVcc
//
//Description: A single sample is made on A0 with reference to AVcc.
//Software sets ADC12SC to start sample and conversion - ADC12SC
//automatically cleared at EOC. ADC12 internal oscillator times sample (16x)
// and conversion. In Mainloop MSP430 waits in LPM0 to save power until ADC12
// conversion complete, ADC12 ISR will force exit from LPM0 in Mainloop on
   reti. If A0 > 0.5*AVcc, P5.1 set, else reset.
   ACLK = 32kHz, MCLK = SMCLK = default DCO 1048576Hz, ADC12CLK = ADC12OSC
//
11
                MSP430xG461x
//
11
         /1\1
                          XIN|-
//
                             | 32kHz
//
           --|RST
                         XOUT | -
//
      Vin -->|P6.0/A0 P5.1|--> LED
//
11
11
    A. Dannenberg/ M. Mitchell
    Texas Instruments Inc.
    October 2006
    Built with CCE Version: 3.2.0 and IAR Embedded Workbench Version: 3.41A
//*********************
#include "msp430xG46x.h"
```



ADC12 Demo: A0 Compare

```
void main(void)
  WDTCTL = WDTPW + WDTHOLD; // Stop WDT
  ADC12CTL0 = SHT0 2 + ADC12ON; // Sampling time, ADC12 on
  ADC12CTL1 = SHP; // Use sampling timer
  ADC12IE = 0x01; // Enable interrupt
  ADC12CTL0 |= ENC;
  P6SEL |= 0x01; // P6.0 ADC option select
  P5DIR \mid = 0 \times 02; // P5.1 output
  while (1)
    ADC12CTL0 |= ADC12SC; // Start sampling/conversion
     bis SR register(LPM0 bits + GIE);
    // LPM0, ADC12 ISR will force exit
#pragma vector = ADC12 VECTOR
 interrupt void ADC12 ISR(void)
  if (ADC12MEM0 >= 0x7ff) // ADC12MEM = A0 > 0.5AVcc?
    P5OUT |= 0x02;
                           // P5.1 = 1
  else
    P5OUT &= \sim 0 \times 02; // P5.1 = 0
   bic SR register on exit(LPM0 bits); // Exit LPM0
```

DAC12 Introduction

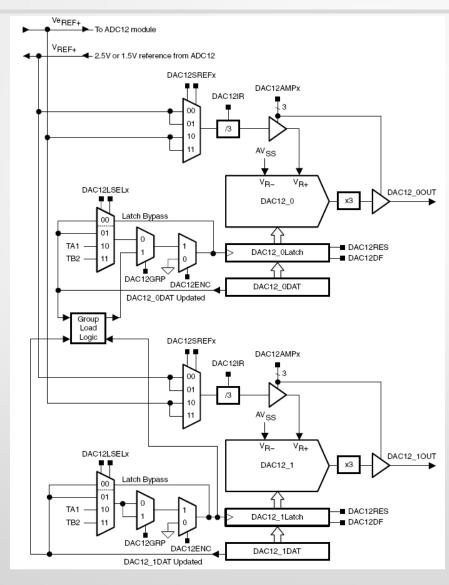
- 12-bit, voltage output DAC.
 - The DAC12 can be configured in 8-bit or 12-bit mode and may be used in conjunction with the DMA controller
 - When multiple DAC12 modules are present, they may be grouped together for synchronous update operation.
- Features of the DAC12 include:
 - 12-bit monotonic output
 - 8-bit or 12-bit voltage output resolution
 - Programmable settling time vs power consumption
 - Internal or external reference selection
 - Straight binary or 2s compliment data format
 - Self-calibration option for offset correction
 - Synchronized update capability for multiple DAC12s



ADC12



DAC12 Block Diagram



DAC12 Core

DAC12RES

AD Conversion Principles

- 0 12-bit
- 1 − 8-bit
- DAC12IR
 - 0 3x
 - 1 1x

Resolution	DAC12RES	DAC12IR	Output Voltage Formula
12 bit	0	0	Vout = Vref \times 3 \times $\frac{DAC12_xDAT}{4096}$
12 bit	0	1	Vout = Vref $\times \frac{DAC12_xDAT}{4096}$
8 bit	1	0	Vout = Vref \times 3 \times DAC12_xDAT
8 bit	1	1	$Vout = Vref \times \frac{DAC12_xDAT}{256}$

DAC12 Port Selection

- DAC12 outputs are multiplexed with the port P6 pins and ADC12 analog inputs, and also the VeREF+ and P5.1/S0/A12 pins
 - When DAC12AMPx > 0, the DAC12 function is automatically selected for the pin, regardless of the state of the associated PxSELx and PxDIRx bits.
- The DAC12OPS bit selects between the P6 pins and the VeREF+ and P5.1 pins for the DAC outputs.
 - For example, when DAC12OPS = 0, DAC12_0 outputs on P6.6 and DAC12_1 outputs on P6.7.
 - When DAC12OPS = 1, DAC12_0 outputs on VeREF+ and DAC12_1 outputs on P5.1.
 - See the port pin schematic in the device-specific datasheet for more details.



DAC12 Reference

- On MSP430FG43x and MSP430FG461x devices, the reference for the DAC12 is configured to use either an external reference voltage or the internal 1.5-V/2.5-V reference from the ADC12 module with the DAC12SREFx bits
- When DAC12SREFx = {0,1} the VREF+ signal is used as the reference and when DAC12SREFx = {2,3} the VeREF+ signal is used as the reference
- To use an ADC internal reference, it must be enabled and configured via the applicable ADC control bits.
- DAC12 voltage output buffers
 - Reference input and voltage output buffers of the DAC12 can be configured for optimized settling time vs power consumption
 - Eight combinations are selected using the DAC12AMPx bits.
 - In the low/low setting, the settling time is the slowest, and the current consumption of both buffers is the lowest.
 - The medium and high settings have faster settling times, but the current consumption increases.
 - See the device-specific data sheet for parameters.



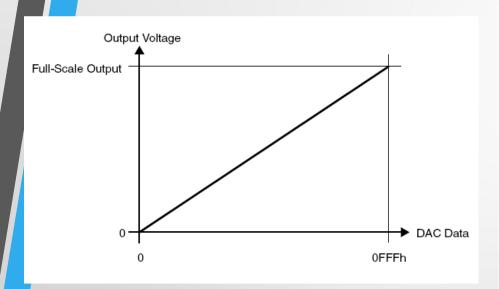
Updating the DAC12 Voltage Output

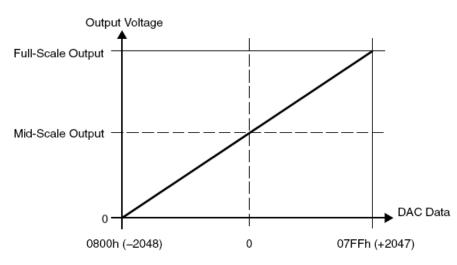
- DAC12 xDAT register can be connected directly to the DAC12 core or
- double buffered.
- The trigger for updating the DAC12 voltage output is selected with the DAC12LSELx bits.
 - When DAC12LSELx = 0 the data latch is transparent and the DAC12_xDAT register is applied directly to the DAC12 core. The DAC12 output updates immediately when new DAC12 data is written to the DAC12_xDAT register, regardless of the state of the DAC12ENC bit.
 - When DAC12LSELx = 1, DAC12 data is latched and applied to the DAC12 core after new data is written to DAC12_xDAT.
 - When DAC12LSELx = 2 or 3, data is latched on the rising edge from the Timer_A CCR1 output or Timer_B CCR2 output respectively. DAC12ENC must be set to latch the new data when DAC12LSELx > 0.





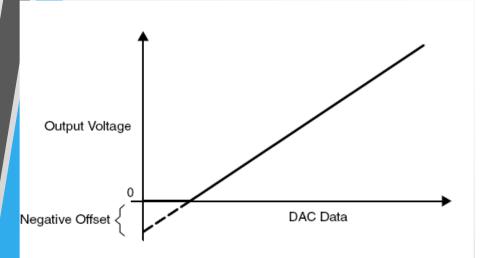
DAC12_xDAT Data Format

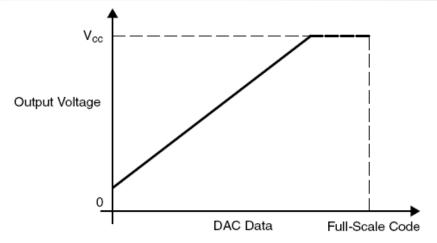






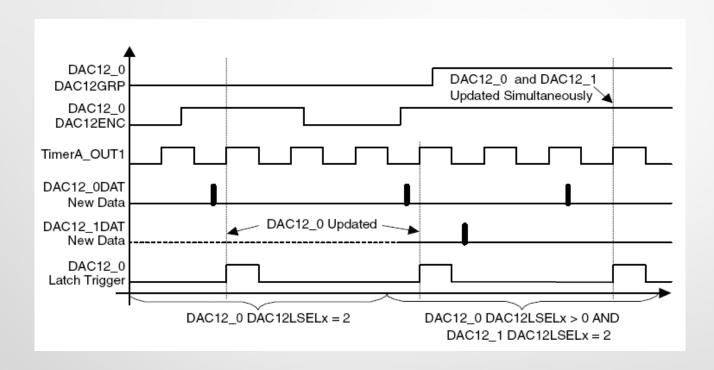
Offset Calibration





ADC12

DAC12 Group Update





DAC12 Demo: RAMP Signal

```
//**************************
// MSP430xG461x Demo - DAC12 0, Output Voltage Ramp on DAC0
// Description: Using DAC12 0 and 2.5V ADC12REF reference with a gain of 1,
// output positive ramp on P6.6. Normal mode is LPMO with CPU off. WDT used
// to provide ~0.064ms interrupt used to wake up the CPU and update the DAC
// with software. Use internal 2.5V Vref.
// ACLK = 32kHz, SMCLK = MCLK = WDTCLK = default DCO 1048576Hz
11
11
11
                MSP430xG461x
          71\1
//
                           XIN|-
                              | 32kHz
           --|RST
                          XOUT | -
//
                     DAC0/P6.6|--> Ramp positive
#include "msp430xG46x.h"
```

DAC12 Demo: RAMP Signal

```
void main(void)
 WDTCTL = WDT MDLY 0 064; // WDT ~0.064ms interval timer
 IE1 |= WDTIE;
                            // Enable WDT interrupt
 ADC12CTL0 = REF2 5V + REFON; // Internal 2.5V ref on
 TACCR0 = 13600; // Delay to understand the CCTE: // Compare-mode interrupt.
                            // Delay to allow Ref to settle
 TACTL = TACLR + MC 1 + TASSEL 2; // up mode, SMCLK
  bis SR register(LPMO bits + GIE); // Enter LPMO, enable int.
 TACCTLO &= ~CCIE;
                                    // Disable timer interrupt
                                    // Disable Interrupts
 disable interrupt();
 DAC12 OCTL = DAC12IR + DAC12AMP 5 + DAC12ENC; // Int ref gain 1
 while (1)
    bis SR register(LPM0 bits + GIE); // Enter LPM0, interrupts enabled
                                        // Positive ramp
   DAC12 ODAT++;
   DAC12 ODAT &= 0x0FFF;
#pragma vector = TIMERAO VECTOR
 interrupt void TAO ISR(void)
                                        // Clear Timer A control registers
  TACTL = 0;
  bic SR register on exit(LPMO bits); // Exit LPMx, interrupts enabled
#pragma vector = WDT VECTOR
 interrupt void WDT ISR(void)
  bic SR register on exit(LPM0 bits); // TOS = clear LPM0
```